

IPD78CN10N G Datasheet

N-Channel 100 V (D-S) MOSFET

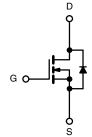
PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A)	Q _g (Typ.)			
	0.055 at $V_{GS} = 10 \text{ V}$	25				
100	0.057 at V _{GS} = 4.5 V	25	21nC			

FEATURES

- TrenchFET® power MOSFET
- 100 % UIS tested

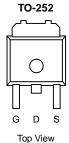


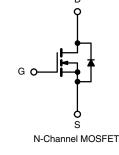




APPLICATIONS

· Primary side switch





PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage	V _{DS}	100	V		
Gate-Source Voltage	V _{GS}	± 20			
	T _C = 25 °C		25		
Continuous Drain Current /T 175 °C)	T _C = 70 °C		20		
Continuous Drain Current (T _J = 175 °C)	T _A = 25 °C	I _D	12 ^{b, c}		
	T _A = 70 °C		10 b, c		
Pulsed Drain Current	I _{DM}	75	A		
Continuous Course Ducis Diada Course	T _C = 25 °C		50 ^e		
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	6.9 b, c		
Avalanche Current Pulse		I _{AS}	33		
Single Pulse Avalanche Energy	L = 0.1 mH	E _{AS}	55	mJ	
	T _C = 25 °C		83	w	
Mayimum Dawar Dissination	T _C = 70 °C	D	58		
Maximum Power Dissipation	T _A = 25 °C	P _D	8.3 b, c		
	T _A = 70 °C		5.8 b, c		
Operating Junction and Storage Temperature R	T _J , T _{stg}	-55 to +175	°C		

THERMAL RESISTANCE RATINGS							
PARAMETER		SYMBOL	TYPICAL	MAXIMUM	UNIT		
Maximum Junction-to-Ambient b, d	t ≤ 10 s	R_{thJA}	15	18	°C/W		
Maximum Junction-to-Case	Steady State	R_{thJC}	1.5	1.8	C/VV		

Notes

- a. Based on T_C = 25 °C.
- b. Surface mounted on 1" x 1" FR4 board.
- d. Maximum under steady state conditions is 50 °C/W.
- e. Calculated based on maximum junction temperature. Package limitation current is 50 A.



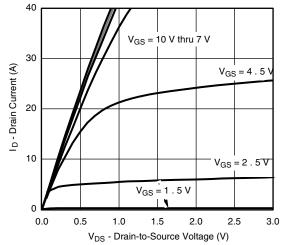
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static						
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA	100	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J 050 A	-	165	-	mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	$I_D = 250 \mu\text{A}$	-	-11	-	mv/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	0.8	1.2	1.6	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	-	-	± 100	nA
Zero Gate Voltage Drain Current	Inno	V _{DS} = 100 V, V _{GS} = 0 V	1		1	μА
Zero date voltage Drain Guirent	$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 \text{ °C}$		-	-	10	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	25	-	-	Α
Drain-Source On-State Resistance a	R _{DS(on)}	$V_{GS} = 10 \text{ V}, I_{D=12A}$	- 0.055			Ω
Drain Godice on Glate Resistance	TIDS(on)	V_{GS} =4.5 V, I_D =8A		0.057		32
Forward Transconductance a	g _{fs}	$V_{DS} = 15 \text{ V}, I_D = 12 \text{ A}$	-	25	-	S
Dynamic ^b						
Input Capacitance	C _{iss}		-	1800	-	pF
Output Capacitance	Coss	$V_{DS} = 12 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-	180	-	
Reverse Transfer Capacitance	C _{rss}		-	60	-	
Total Gate Charge	Q_g		-	21	32	nC
Gate-Source Charge	Q _{gs}	$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 12 \text{ A}$	-	10	-	
Gate-Drain Charge	Q_{gd}		-	9	-	
Gate Resistance	R_g	f = 1 MHz	-	1.5	-	Ω
Turn-On Delay Time	t _{d(on)}		-	10	15	- ns
Rise Time	t _r	$V_{DD} = 50 \text{ V}, R_L = 5 \Omega$	-	10	15	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10$ A, $V_{GEN} = 10$ V, $R_g = 1$ Ω	-	15	25	
Fall Time	t _f		-	10	15	
Drain-Source Body Diode Characteristic	s		L	l	L	
Continuous Source-Drain Diode Current	Is	T _C = 25 °C	-	-	50	
Pulse Diode Forward Current ^a	I _{SM}		-	-	40	A
Body Diode Voltage	V_{SD}	I _S = 10 A	-	0.8	1.2	V
Body Diode Reverse Recovery Time	t _{rr}		-	50	75	ns
Body Diode Reverse Recovery Charge	Q _{rr}		-	100	150	nC
Reverse Recovery Fall Time	t _a	$I_F = 10 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$	-	38	-	
Reverse Recovery Rise Time	t _b	\dashv		12	_	ns

Note

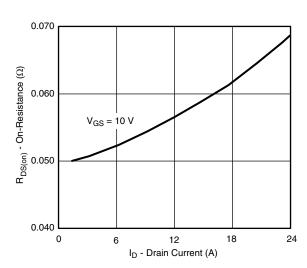
- a. Pulse test; pulse width $\leq 300~\mu\text{s},$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

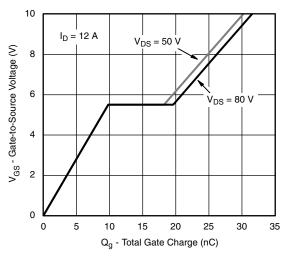




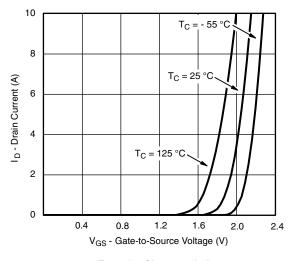




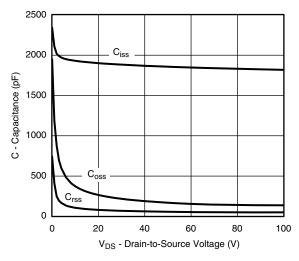
On-Resistance vs. Drain Current



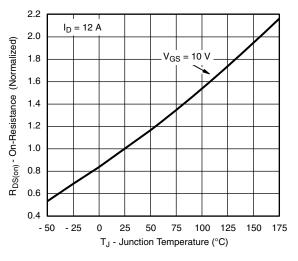
Gate Charge



Transfer Characteristics

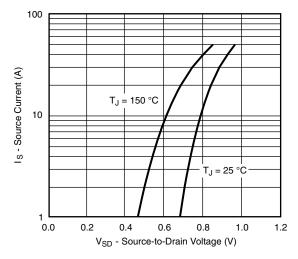


Capacitance

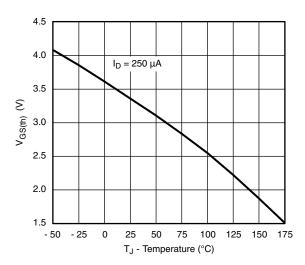


On-Resistance vs. Junction Temperature

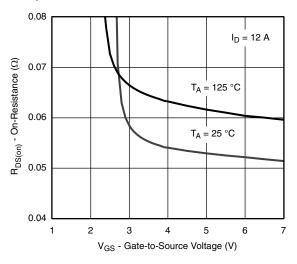




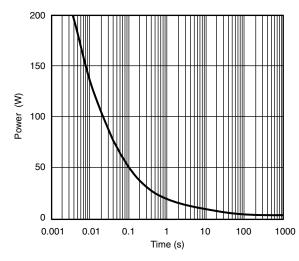
Source-Drain Diode Forward Voltage



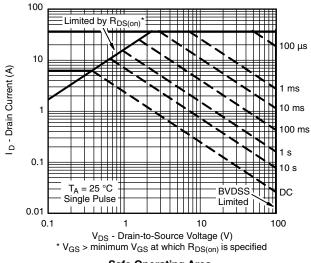
Threshold Voltage



 $R_{DS(on)}$ vs. V_{GS} vs. Temperature

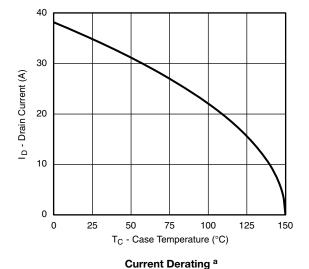


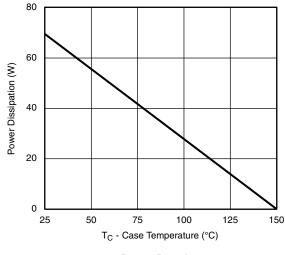
Single Pulse Power, Junction-to-Ambient



Safe Operating Area





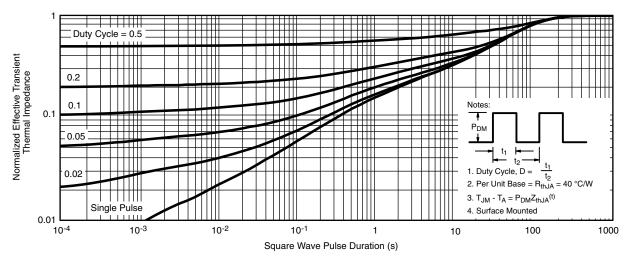


Power Derating

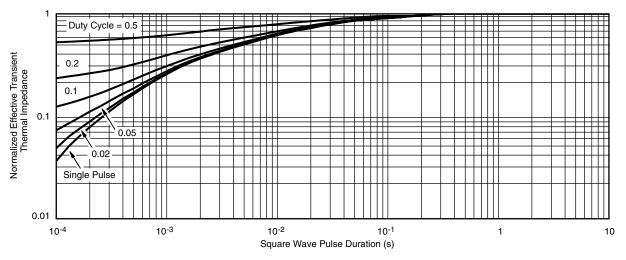
Note

a. The power dissipation P_D is based on T_J (max.) = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





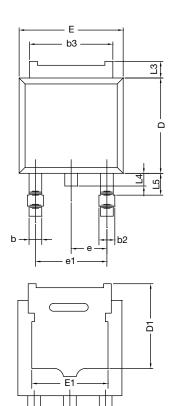
Normalized Thermal Transient Impedance, Junction-to-Ambient

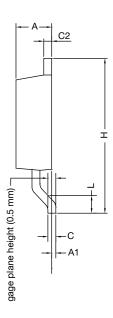


Normalized Thermal Transient Impedance, Junction-to-Case



TO-252AA Case Outline





	MILLIN	METERS	INC	HES		
DIM.	MIN.	MAX.	MIN.	MAX.		
Α	2.18	2.38	0.086	0.094		
A1	-	0.127	-	0.005		
b	0.64	0.88	0.025	0.035		
b2	0.76	1.14	0.030	0.045		
b3	4.95	5.46	0.195	0.215		
С	0.46	0.61	0.018	0.024		
C2	0.46	0.89	0.018	0.035		
D	5.97	6.22	0.235	0.245		
D1	4.10	-	0.161	-		
Е	6.35	6.73	0.250	0.265		
E1	4.32	-	0.170	-		
Η	9.40	10.41	0.370	0.410		
e	2.28 BSC		0.090 BSC			
e1	4.56 BSC		0.180 BSC			
L	1.40	1.78	0.055	0.070		
L3	0.89	1.27	0.035	0.050		
L4	-	1.02	-	0.040		
L5	1.01	1.52	0.040	0.060		
ECN: T16-0236-Rev. P, 16-May-16						

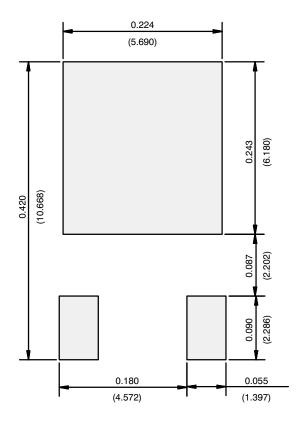
DWG: 5347 Notes

• Dimension L3 is for reference only.

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RECOMMENDED MINIMUM PADS FOR DPAK (TO-252)



Recommended Minimum Pads Dimensions in Inches/(mm)



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